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DIODES, POWER RECTIFIER, SCHOTTKY BARRIER

BASED ON TYPE STPS20100

ESCC Detail Specification No. 5106/016



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ESCC Detail Specification

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1 **GENERAL**

1.1 SCOPE

This specification details the ratings, physical and electrical characteristics and test and inspection data for the component type variants and/or the range of components specified below. It supplements the requirements of, and shall be read in conjunction with, the ESCC Generic Specification listed under Applicable Documents.

1.2 APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:

- (a) ESCC Generic Specification No. 5000
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices

1.3 TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESCC Basic Specification No. 21300 shall apply.

1.4 THE ESCC COMPONENT NUMBER AND COMPONENT TYPE VARIANTS

1.4.1 The ESCC Component Number

The ESCC Component Number shall be constituted as follows:

Example: 510601601

Detail Specification Reference: 5106016

Component Type Variant Number: 01 (as required)

1.4.2 Component Type Variants

The component type variants applicable to this specification are as follows:

Variant Number	Based on Type	Case	Description	Lead/Terminal Material and Finish	Weight max g
01	STPS20100	TO-254	Single diode	H9	10
02	STPS20100	TO-254	Dual diode, common anode	Н9	10
03	STPS20100	TO-254	Dual diode, common cathode	Н9	10
04	STPS20100	TO-254	Dual diode, series, centre tapped	Н9	10
05	STPS20100	SMD.5	Single diode	Q14	2
06	STPS20100	SMD1	Single diode	Q14	3



Variant Number	Based on Type	Case	Description	Lead/Terminal Material and Finish	Weight max g
07	STPS20100	SMD1	Dual diode, common cathode	Q14	3

The lead/terminal material and finish shall be in accordance with the requirements of ESCC Basic Specification No. 23500.

1.5 <u>MAXIMUM RATINGS</u>

The maximum ratings shall not be exceeded at any time during use or storage.

Maximum ratings shall only be exceeded during testing to the extent specified in this specification and when stipulated in Test Methods and Procedures of the ESCC Generic Specification.

Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Forward Surge Current (per Diode)	I _{FSM}	250	А	Note 1
Repetitive Peak Reverse Voltage	V_{RRM}	100	V	Note 2
Repetitive Peak Reverse Current	I _{RRM}	1	А	Note 3
Average Output Rectified Current	I _O		А	50% duty cycle Notes 4, 9
All Variants (per Diode)		20		
Variants 02, 03 and 07 (per Device)		40		
RMS Forward Current (Per Diode)	I _{F(rms)}	30	Α	
Operating Temperature Range (Case Temperature)	T _{op}	-65 to +175	°C	Note 5
Junction Temperature	TJ	+175	°C	
Storage Temperature Range	T _{stg}	-65 to +175	°C	Note 5
Soldering Temperature	T _{sol}		°C	
For TO-254		+260		Note 6
For SMD.5 and SMD1		+245		Note 7
Critical Rate of Rise of Reverse Voltage	dV/dt	10000	V/μs	



Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Thermal Resistance, Junction to Case	R _{th(j-c)}		°C/W	Notes 8, 9
Variants 01, 05 and 06		1.65		
Variants 02 to 04 and 07 (per Diode)		1.65		
Variants 02, 03 and 07 (per Device)		0.85		

NOTES:

- 1. Sinusoidal pulse of 10ms duration.
- 2. Pulsed, duration 5ms, f = 50Hz.
- 3. Pulsed, duration $2\mu s$, f = 1kHz.
- 4. For $T_{case} > +140$ °C, derate linearly to 0A at +175 °C.
- 5. For Variants with hot solder dip lead finish all testing performed at T_{amb} > +125 °C shall be carried out in a 100% inert atmosphere.
- 6. Duration 10 seconds maximum at a distance of not less than 1.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.
- 7. Duration 5 seconds maximum and the same package shall not be resoldered until 3 minutes have elapsed.
- 8. Package mounted on infinite heatsink.
- 9. The "per Device" ratings apply only as follows:
 - Variant 02: when both cathode terminals are tied together.
 - Variants 03 and 07: when both anode terminals are tied together.

1.6 HANDLING PRECAUTIONS

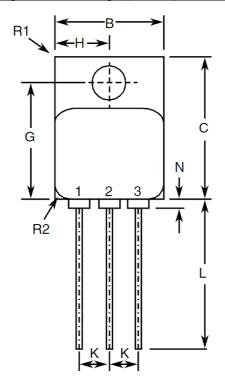
The TO-254 package contains Beryllium Oxide (BeO) and therefore it must not be ground, machined, sandblasted or subjected to any mechanical operation which will produce dust. The case must not be subjected to any chemical process (e.g. etching) which will produce fumes.

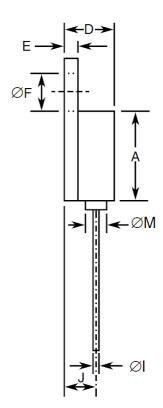
1.7 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION

Consolidated Notes are given following the case drawings and dimensions.



1.7.1 Metal Flange Mount Package (TO-254) - 3 lead



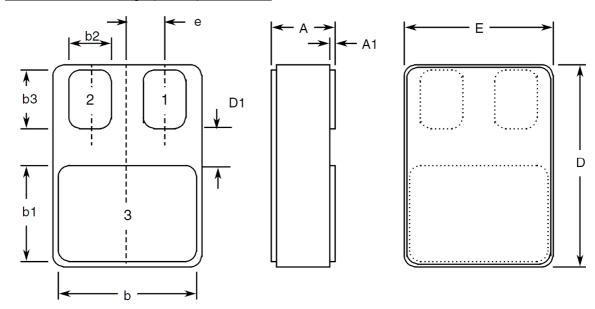


O. made a la	Dimensions mm		Notes
Symbols	Min	Max	Notes
А	13.59	13.84	
В	13.59	13.84	
С	20.07	20.32	
D	6.3	6.7	
E	1	1.35	
ØF	3.5	3.9	
G	16.89	17.4	
Н	6.86	BSC	
ØI	0.89	1.14	2
J	3.81	BSC	
К	3.81 BSC		
L	12.95	14.5	
ØM	3.05 Typical		2
N	-	0.71	2



O make a la	Dimensi	Notos	
Symbols	Min	Max	Notes
R1	-	1	3
R2	1.65 Typical		4

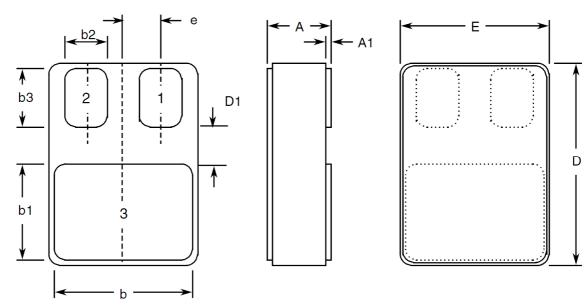
1.7.2 Surface Mount Package (SMD.5) - 3 terminal



Symbols	Dimensi	Notes	
	Min	Max	Notes
А	2.84	3.15	
A1	0.25	0.51	
b	7.13	7.39	
b1	5.58	5.84	
b2	2.28	2.54	5
b3	2.92	3.18	5
D	10.03	10.28	
D1	0.76	-	5
E	7.39	7.64	
е	1.91 BSC		5



1.7.3 Surface Mount Package (SMD1) - 3 terminal



Symbols	Dimensi	Notes	
Symbols	Min	Max	notes
А	3.3	3.61	
A1	0.25	0.51	
b	9.4	9.65	
b1	10.41	10.67	
b2	3.43	3.68	5
b3	3.86	4.11	5
D	15.75	16	
D1	0.76	•	5
E	11.3	11.56	
е	2.67 BSC		5

1.7.4 <u>Notes to Physical Dimensions and Terminal Identification</u>

- 1. The terminal identification is specified by the component's geometry. See Functional Diagram for the terminal connections.
- 2. 3 places.
- 3. Radius of heatsink flange corner, 4 places.
- 4. Radius of body corner, 4 places.
- 5. 2 places.



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FUNCTIONAL DIAGRAM 1.8

Terminal 1: Cathode

Terminal 2: No connection

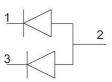
Terminal 3: Anode

Variant 01



Variant 02

Terminal 1: Cathode a Terminal 2: Common Anode Terminal 3: Cathode b

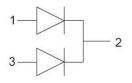


Variant 03

Terminal 1: Anode a

Terminal 2: Common Cathode

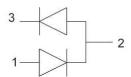
Terminal 3: Anode b



Variant 04

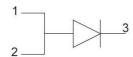
Terminal 1: Anode a Terminal 2: Centre Tap

Terminal 3: Cathode b



Variants 05 and 06

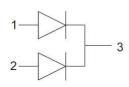
Terminals 1 and 2: Anode Terminal 3: Cathode



Variant 07

Terminal 1: Anode a Terminal 2: Anode b

Terminal 3: Common Cathode



NOTES:

- For TO-254, the case is not connected to any lead.
- For SMD.5 and SMD1, the lid is not connected to any terminal.



1.9 MATERIALS AND FINISHES

Materials and finishes shall be as follows:

(a) Case

For the metal flange mount package the case shall be hermetically sealed and have a metal body. The leads pass through ceramic eyelets brazed into the frame and the lid shall be welded.

For the surface mount packages the case shall be hermetically sealed and have a ceramic body with a Kovar lid.

(b) Leads/Terminals

As specified in Component Type Variants.

2 REQUIREMENTS

2.1 GENERAL

The complete requirements for procurement of the components specified herein are as stated in this specification and the ESCC Generic Specification. Permitted deviations from the Generic Specification, applicable to this specification only, are listed below.

Permitted deviations from the Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESCC requirement and do not affect the component's reliability, are listed in the appendices attached to this specification.

2.1.1 <u>Deviations from the Generic Specification</u>

2.1.1.1 Deviation from Screening Tests - Chart F3

(a) High Temperature Reverse Bias Burn-in and the subsequent Final Measurements for HTRB shall be omitted.

2.1.1.2 Deviations from Qualification and Periodic Tests - Chart F4

- (a) Constant Acceleration is not applicable.
- (b) For SMD.5 and SMD1, Terminal Strength is not applicable.

2.2 MARKING

The marking shall be in accordance with the requirements of ESCC Basic Specification No. 21700 and as follows.

The information to be marked on the component shall be:

- (a) The ESCC qualified components symbol (for ESCC qualified components only).
- (b) The ESCC Component Number.
- (c) Traceability information.
- (d) Warning sign for Beryllium Oxide (TO-254 only).



2.3 TERMINAL STRENGTH

The test conditions for Terminal Strength, tested as specified in the ESCC Generic Specification, shall be as follows:

For TO-254, Test Condition: A, tension, with an applied force of 10N and a duration of 10s.

2.4 <u>ELECTRICAL MEASUREMENTS AT ROOM, HIGH AND LOW TEMPERATURES</u>

Electrical measurements shall be performed at room, high and low temperatures. Consolidated notes are given after the tables.

2.4.1 Room Temperature Electrical Measurements

The measurements shall be performed at T_{amb} = +22 ±3 °C.

Characteristics			Limits		Units	
		Test Method	Note 1	Min	Max	
Reverse Current	I _R	4016	DC Method V _R = 100V	-	30	μΑ
Forward Voltage	V _{F1}	4011	Pulse Method I _F = 10A Note 2	-	780	mV
	V _{F2}	4011	Pulse Method I _F = 20A Note 2	-	1	>
Capacitance	С	4001	V _R = 10V f = 1MHz	-	700	pF
Thermal Impedance, Junction to Case	Z _{th(j-c)}	3101	I_H = 15 to 40A t_H = 50ms I_M = 50mA t_{md} = 100 μ s Note 3	`	ate ΔV_F , lote 4)	°C/W



2.4.2 High and Low Temperatures Electrical Measurements

Characteristics				Limits		Units
		Test Method	hod Notes 1 and 5		Max	
Reverse Current	I _R	4016	T_{case} = +125 (+0 -5) °C DC Method V_R = 100V	1	20	mA
Forward Voltage 2	V _{F2}	4011	T_{case} = +125 (+0 -5) °C Pulse Method I_F = 20A Note 2	-	900	mV
			T_{case} =-55 (+5 -0) °C Pulse Method I_F = 20A Note 2	-	1.1	V

2.4.3 Notes to Electrical Measurement Tables

- Measurement per each diode.
- 2. Pulse Width ≤ 680µs, Duty Cycle ≤ 2%.
- 3. Performed only during Screening Tests Parameter Drift Values (Initial Measurements), go-no-go.
- 4. The limits for ΔV_F shall be defined by the Manufacturer on every lot in accordance with MIL-STD-750 Method 3101 and shall guarantee the $R_{th(j-c)}$ limits specified in Maximum Ratings.
- 5. Read and record measurements shall be performed on a sample of 5 components with 0 failures allowed. Alternatively a 100% inspection may be performed.

2.5 PARAMETER DRIFT VALUES

Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3 °C.

The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.

The drift values (Δ) shall not be exceeded for each characteristic specified. The corresponding absolute limit values for each characteristic shall not be exceeded.

Characteristics	Symbols	Limits		Units	
		Drift	Absolute		
		Value Δ	Min	Max	
Reverse Current	I _R	±4 or (1) ±100%	-	30	μА
Forward Voltage 1	V _{F1}	±10	-	780	mV

NOTES:

1. Whichever is the greater referred to the initial value.



2.6 INTERMEDIATE AND END-POINT ELECTRICAL MEASUREMENTS

Unless otherwise specified, the measurements shall be performed at T_{amb} = +22 ±3 °C.

The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.

The limit values for each characteristic shall not be exceeded.

Characteristics	Symbols	Lin	nits	Units
		Min	Max	
Reverse Current	I _R	-	30	μΑ
Forward Voltage 1	V _{F1}	-	780	mV

2.7 POWER BURN-IN CONDITIONS

Characteristics	Symbols	Symbols Test Conditions	
Case Temperature	T _{case}	+125	°C
Reverse Voltage	V _R	80	V

2.8 OPERATING LIFE CONDITIONS

The conditions shall be as specified for Power Burn-in.



APPENDIX 'A' AGREED DEVIATIONS FOR STMICROELECTRONICS (F)

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Deviations from Production Control - Chart F2	Special In-Process Controls - Internal Visual Inspection. Wedge bonds equal to 1.1 wire diameter are acceptable for bonding with a V-Groove tool.
Deviations from Screening Tests - Chart F3	Solderability is not applicable unless specifically stipulated in the Purchase Order.